

Cp E 432: Testing of Computing Systems ELECTRICAL ENGINEERING

Physical defects from semiconductor manufacture, fault modeling and simulation, fault activation and detection in digital systems, digital test pattern synthesis, test coverage, test compaction, online/offline/BIST testing concepts, design-for-test, design-for- manufacture, system testability and diagnosability. 3 Credits

Prerequisites

- El E 351: Models and Circuits I
- El E 385: Advanced Digital Systems
- El E 386: Advanced Digital Systems Laboratory

Instruction Type(s)

• Lecture: Lecture for Cp E 432

Subject Areas

• Computer Engineering, General

Related Areas

Computer Hardware Engineering

The University of Mississippi is accredited by the Southern Association of Colleges and Schools Commission on Colleges to award certificates and baccalaureate, master's, specialist, and doctoral degrees. Contact the Commission on Colleges at 1866 Southern Lane, Decatur, Georgia 30033-4097, call 404-679-4500, or visit online at www.sacscoc.org for questions about the accreditation.

